Evaluation of Uncertainties in Atomic Data on Spectral Lines and Transition Probabilities

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Introduction: "data" vs "numbers"

Ratio of circumference to diameter: $L / D = \pi$, $\pi = 3.1415...$ is a *number*



Uncertainty is intrinsic part of data and cannot be omitted

Measurement *data* for *D*: 1.9005 ± 0.0005 1.9001 ± 0.0005 1.9010 ± 0.0005 1.9008 ± 0.0005 1.9003 ± 0.0005





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Uncertainties in wavelength measurements

Guides for evaluating and expressing uncertainty in measurementsGUM (BIPM):https://www.bipm.org/en/committees/jc/jcgm/publicationsNIST TN1297:http://physics.nist.gov/TN1297NIST TN1900:https://doi.org/10.6028/NIST.TN.1900NUM:https://uncertainty.nist.gov/

Despite the availability of guides, uncertainty of a weighted mean is still controversial



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Uncertainty of weighted mean: example

Measurement 1: $G = 6.67430(15) [\times 10-11 \text{ m}^3/(\text{kg s}^2)] - \text{CODATA2018}$ Measurement 2: G = 6.690(3) [...] - Undergraduate physics experiment

Weighted mean (standard statistics): $v_{wm} = \sum v_i w_i / \sum w_i$, $w_i = 1/u_i^2$ Uncertainty of wm: $u_{wm} = 1/\sqrt{\sum w_i}$

*G*_{wm} = 6.67434(15) [...] – "biased" uncertainty?

Unbiased unc. of wm (https://en.wikipedia.org/wiki/Weighted arithmetic mean): $u_{\text{biased}}^2 = \sum w_i (v_i - v_{\text{wm}})^2 / V_1; \quad u_{\text{unbiased}} = u_{\text{biased}} / \sqrt{1 - V_2 / V_1^2}$ $V_1 = \sum w_i; \quad V_2 = \sum w_i^2$

 $u_{\rm biased} = 0.00080$

$$u_{\text{unbiased}} = 0.01100$$
 [...]

Error: WRONG STATISTICAL MODEL

The two measurements are *inhomogeneous*



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Dark Uncertainties in Heterogeneous Measurements

Measurement 1: $G = 6.67430(15) [\times 10-11 \text{ m}^3/(\text{kg s}^2)] - \text{CODATA2018}$ Measurement 2: G = 6.690(3) [...] - Undergraduate physics experiment

Weighted mean with dark unc.: $v_{wm} = \sum v_i w_i / \sum w_i$, $w_i = 1/(u_i^2 + d_i^2)$ Uncertainty of wm: $u_{wm} = 1/\sqrt{\sum w_i}$

> A. L. Rukhin, <u>Metrologia 56, 035002 (2019)</u>: Clustered Maximum Likelihood Estimator (CMLE) Clustered Reduced Maximum Likelihood Estimator (CRMLE)

 $d_1 = 0, d_2 = 0.016 \rightarrow G_{wm} = 6.67430(15) [...] - Justice restored!$

Wavelength measurements are *inhomogeneous* (different line profiles, blending, Stark shifts, ...)



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Physics of the outlying measurement



Statistics can help to spot and localize the problem, but physics must be used to solve it.



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Spotting outliers in "observed-Ritz" differences

FTS lines of Zr I and Zr II, J.E. Lawler, J.R. Schmidt, E.A. Den Hartog, JQSRT 289, 108283 (2022)

$\sigma_{ m obs}$, cm ⁻¹	N _{spectra}	E low	E _{upp}	$\Delta \sigma_{ m obs-Ritz}$	DU _{MP}	DU _{CMLE}
14473.2603 <mark>(15)</mark>	4	11016.6440	25489.8995	0.0048	0.0051	<mark>0.0062</mark>
14604.5628 <mark>(15)</mark>	4	10885.3362	25489.8995	-0.0005	0.0051	0.0000
21303.8870 <mark>(26)</mark>	3	4186.0080	25489.8995	-0.0045	0.0051	0.0000
25489.8915 <mark>(25)</mark>	2	0.0000	25489.8995	-0.0080	0.0051	<mark>0.0062</mark>

Treat as measured quantity with same uncertainties as $\sigma_{\rm obs}$

Do not blindly add dark uncertainties to observed ones. This does not eliminate physical errors and may accentuate them.



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Uncertainties in calculated transition probabilities

Use line strength S as discriminating quantity.

A. Kramida, Fusion Sci. Technol. 63, 313 (2013); Atoms 2, 86 (2014)



Problem: line strength *S* is not always the best discriminating quantity to correlate with uncertainties



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Comparison of length and velocity forms

C. Froese Fischer, Phys. Scr. T134, 014019 (2009)

J. Ekman, M.R. Godefroid, H. Hartman, Atoms 2, 215 (2014)

GRASP2018: C. Froese Fischer, G. Gaigalas, P. Jönsson, J. Bieroń, CPC 237, 184 (2019)

Uncertainty *indicator* $dT = \frac{|A_l - A_v|}{\max(A_l, A_v)}$

Caveats:

- *dT* is not uncertainty! Only an indicator that must be treated statistically. Too often, $A_l \approx A_v$ but both are wrong!
- Because of max() in denominator, *dT* always underestimates uncertainties. Better use min().

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Better indicator of uncertainty

A. Kramida, <u>Fusion Sci. Technol. 63</u>, 313 (2013) F. El-Sayed, <u>JQSRT 254</u>, 107204 (2020)

 $dL = \ln(S_1/S_2)$

 S_1 and S_2 are any two forms of line strength of the same transition. Uncertainty in S:

 $u_S \approx e^{\langle dL \rangle} - 1$

Caveat:

Neither *dT* nor *dL* are statistically justified: their statistical distributions are not normal. $\left[\left(\frac{S_1}{S_2}\right)^{\frac{1}{3}} - 1\right] / \left(\frac{1}{3}\right)$ may be better.

A. Kramida, Atoms 2, 86 (2014)



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Dividing transitions into groups: Which parameter does not depend on energy?

Similar S? Similar gA? Similar gf? Similar branching fraction? Similar cancellation factor? A. Kramida, <u>Fusion Sci. Technol. 63</u>, 313 (2013)
M.C. Li, W. Li, P. Jönsson et al., <u>ApJS 265</u>, 26 (2023)
W. Li, A.M. Amarsi, A. Papoulia et al., <u>MNRAS 502</u>, 3780 (2021)
J.Q. Li, C.Y. Zhang, G. Del Zanna et al., <u>ApJS 260</u>, 50 (2022) *No clear example*

I.P. Grant, <u>J. Phys. B 7, 1458 (1974)</u>

Magnetic transitions (L is multipolarity: 1 for dipole, 2 for quadrupole, etc.):

$$S^{\rm m}_{\alpha\beta} \propto \left[\int_0^\infty (P_\alpha Q_\beta - Q_\alpha P_\beta) r^L \,\mathrm{d}r\right]$$

Electric transitions, Babushkin gauge:

$$S^{\mathrm{e}}_{\alpha\beta}(B) \propto \left[\int_{0}^{\infty} R_{\alpha}R_{\beta}r^{L}\mathrm{d}r\right]^{2}$$

Electric transitions, Coulomb gauge:

$$S_{\alpha\beta}^{e}(C) \propto \frac{1}{\omega^{2}} \left[\int_{0}^{\infty} R_{\beta} \left\{ \frac{\mathrm{d}}{\mathrm{d}r} + \frac{(l_{\alpha} - l_{\beta})(l_{\alpha} + l_{\beta} + 1)}{2r} \right\} R_{\alpha} \mathrm{d}r \right]^{2}$$



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Dividing transitions into groups Which parameter does not depend on energy?

Example: resonance lines of H-like ions, $1s-np_{3/2}$, n = 2-6 O. Jitrik, C.F. Bunge, JPCRD **33**, 1059 (2004)



In vast majority of cases, *S* (length form for electric transitions) is empirically found to correlate best with uncertainties.

However, there are exceptions, so one must check if other quantities are better.



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Dividing transitions into groups Which parameter better correlates with uncertainties?

MCDHF calculation for NI: M.C. Li, W. Li, P. Jönsson et al., ApJS 265, 26 (2023)





 $S_{\rm C}/\lambda^2$ is much better than $S_{\rm B}$ in this case, but $gA_{\rm C}$ is better yet.



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Gauge dependence

Z. Rudzikas, Theoretical Atomic Spectroscopy (Cambridge Univ. Press, 2007) X.H. Zhang, G. Del Zanna, K. Wang et al., <u>ApJS **257**</u>, <u>56 (2021)</u> P. Rynkun, S. Banerjee, G. Gaigalas et al., <u>A&A 658</u>, <u>A82 (2022)</u>



This methodology reflects a belief that $|1 - M_B/M_C|$ is never random and always indicates a real accuracy of a calculation.



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Gauge dependence

A. Hibbert, Galaxies 6, 77 (2018)

"However, even though exact agreement between the two forms is achieved in a local potential approximation, the common value is not necessarily correct. It is sometimes possible to achieve good length and velocity agreement even in the HF approximation (a non-local potential method), but again the common value can be incorrect."

Methodology needed:

How to distinguish when closeness of S_B and S_C is a computational artifact, and when it reflects the real accuracy?



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Cancellation factor

P. Rynkun et al., <u>A&A 658, A82 (2022)</u> G. Gaigalas et al., <u>ApJS 248, 13 (2020)</u>



Ce IV, 5s²5p⁶5d ²D_{3/2}– 4f5s²5p^{6 2}F°_{5/2}

Most transitions have the largest CF (better accuracy) for G = 1 or $G = \sqrt{2}$.

The CF calculation should be included in the <u>GRASP</u> package.

M. Bilal et al., <u>PRA 99, 062511 (2019)</u>: For some transitions, velocity form gives more accurate results!



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Dividing transitions into groups: Account for different amount of correlation effects

S. Rathi and L. Sharma, Atoms 10, 131 (2022)



GRASP calculations included virtual excitations to $n \le 11$. Results are given for $n \le 9$. Configurations with $n \le 7$ include more correlations than those with n = 8, 9.

Transitions expected to have different accuracy must be considered separately.



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Uncertainties in computed lifetimes: Comparisons with experiments

No database of critically evaluated lifetimes!

Use the NIST Atomic Transition Probability Bibliographic Database: <u>https://physics.nist.gov/fvalbib</u>

Pay attention to experimental methods: not all are reliable.

Example: beam-foil results using ANDC (newer) are more accurate than ones with simple fitting of decay curves.



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Uncertainties in computed lifetimes: Error propagation

Common error: comparison of τ_{length} and τ_{velocity}

- 1) M1, M2, etc. are not accounted for.
- 2) Same problems as with S_{length} and S_{velocity} .
- 3) Contributions from errors in wavelength to A-values must be accounted for.

Good practice examples:

M.C. Li et al., <u>ApJS **265**</u>, <u>26</u> (2023) (N I); W. Li et al., <u>A&A **674**</u>, <u>A54 (2023)</u> (O I); S. Rathi and L. Sharma, <u>Atoms **10**, <u>131 (2022)</u> (Na-like Ar, Kr, Xe); J. Ruczkowski, M. Elantkowska, <u>JQSRT **277**, <u>107996 (2022)</u> (Sc II).</u></u>

$$\frac{u(\tau_i)}{\tau_i} = \tau_i \sqrt{\sum_k u(A_{ik})^2}$$



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Uncertainties in computed lifetimes: Alternative method

N. Singh et al., JESRP 257, 147205 (2022) – W LXXIII and Au LXXVIII (He-like)



$$\Delta \tau_1 = \frac{\tau_{n=6} - \tau_{n=5}}{\tau_{n=5}}$$

$$\Delta \tau_2 = \frac{\tau_{n=7} - \tau_{n=6}}{\tau_{n=6}}$$



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Conclusions and outlook

New papers on atomic spectroscopy keep being published at a rate of 500 per year



Progress in methods and new ideas are gratifying but insufficient. More effort is needed in methods of uncertainty evaluation.



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